



# Ring charging of a single silicon dangling bond imaged by noncontact atomic force microscopy

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 (Received 25 May 2020; accepted 9 December 2020; published 29 December 2020)

The electrostatic properties of defects of the Si(111)-( $\sqrt{3} \times \sqrt{3}$ ) $R^\circ 30$  surface are studied using noncontact atomic force microscopy and Kelvin probe force microscopy with subnanometer resolution and subelementary charge sensitivity. We identify nonparabolicities in the frequency-voltage spectroscopy of single dangling bonds (DBs), which reveal the transition from empty to single electronically occupied DBs. Kelvin probe imaging reveals that the DB charging, however, occurs with a ring shape with radius  $\sim 500$  pm located along the circumference of the DB wave function. The ring charging is explained by a tip-induced modulation of the hole recombination rate at the DB-substrate interface.

DOI: [10.1103/PhysRevB.102.235433](https://doi.org/10.1103/PhysRevB.102.235433)

## I. INTRODUCTION

Noncontact atomic force microscopy (nc-AFM) and Kelvin probe force microscopy (KPFM) with atomic or submolecular resolution have for the last decade enabled important advances in mapping the structure [1] and electrostatic properties of surfaces, adatoms, and molecules [2–7]. While most studies have been conducted on metal substrates, semiconductors offer large perspectives in terms of confined electronic systems, e.g., quantum dots [8,9]. An ultimate confined system is a surface adatom dangling bond (DB) consisting of a single electronic state in the bandgap of a semiconductor, whose charging can be controlled by a scanning-probe microscope [10,11]. DBs have been proposed for binary logic [12] and data storage [13,14] applications. They reveal a rich fundamental physics, such as polaronic transport [15,16] and carrier dynamics [17,18].

Here, we image silicon DBs from an electrostatic point of view using KPFM techniques. We work on a *p*-doped Si(111) surface, using the Si(111)-( $\sqrt{3} \times \sqrt{3}$ ) $R^\circ 30$  surface reconstruction. The ability to produce *images* of elementary charge features with subnanometer resolution is first demonstrated using buried ionized dopants, surface vacancies, and the DB empty state, which carry, respectively,  $-e$ ,  $0e$ , and  $+e$  charges. Nonparabolicity effects are then identified in the frequency-voltage spectroscopy of single DBs and are attributed to the transition between the empty and the first occupied DB states. KPFM imaging reveals that the DB charging remarkably occurs with a ring shape localized at the periphery of the DB wave function, which is explained by a tip-induced modulation of the carrier recombination rate at the DB-substrate interface. Unveiling such a modulation or gating effect at the subnanometer scale from KPFM mapping illustrates the possibility of gaining new insights into the physics of ultimate confined semiconductor systems using highly resolved nc-AFM techniques, compared to previous scanning

tunneling microscopy studies [19]. It also demonstrates the need for future microscopic theories of such phenomena.

## II. EXPERIMENTAL DETAILS

Experiments have been carried out at  $T = 4$  K using a Joule-Thomson STM/AFM (SPECS, Berlin) with a base pressure of  $10^{-10}$  mbar. The samples consist of *p*-type Si(111)

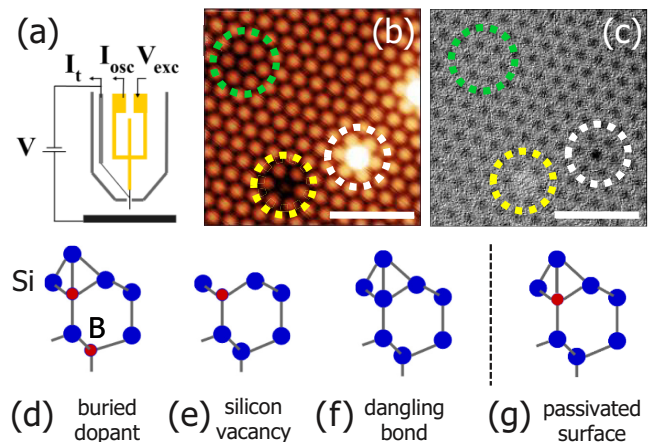


FIG. 1. (a) Length-extensional resonator sensor (yellow) used for STM and nc-AFM.  $V$  is the voltage applied to the sample;  $I_t$ , the tunnel current. The oscillator is excited using a bias  $V_{\text{exc}}$  on the quartz, and the oscillation at the frequency  $f_0 + \Delta f$  is tracked from the current  $I_{\text{osc}}$ . (b) Empty-state STM image ( $V = +1.5$  V,  $I_t = 10$  pA, 160-pm color  $z$  range, 3-nm scale bar) of the Si(111)-( $\sqrt{3} \times \sqrt{3}$ ) $R^\circ 30$  reconstruction. The highlighted defects are a buried dopant (green), a silicon vacancy (yellow), and a silicon DB (white). (c) Corresponding atomic-resolution nc-AFM open-loop frequency shift image (0.3-Hz  $\Delta f$  grayscale), using  $A_{\text{pp}} = 100$  pm. (d–f) Defect structures: buried dopant, vacancy, and DB. (g) Passivated surface adatom of the Si(111)-( $\sqrt{3} \times \sqrt{3}$ ) $R^\circ 30$  reconstruction, corresponding to all atoms visible in (b) and (c) except defects.

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degenerately doped with boron (resistivity of  $\approx 1 \text{ m}\Omega \cdot \text{cm}$  at 300 K), prepared by thermal annealing up to  $1200^\circ\text{C}$  to obtain a  $\text{Si}(111)-(\sqrt{3} \times \sqrt{3})R^{\circ}30$  surface reconstruction (see Refs. [10,13,16,20]) for the surface preparation and defect identification). They have been investigated by scanning tunneling microscopy (STM) and nc-AFM, using length-extensional resonators with W tips (Kolibri sensors; SPECS, Berlin) of oscillation frequency  $f_0 \approx 1 \text{ MHz}$  and quality factor  $Q \approx 10^5$  [21,22]. The tips have been prepared by Ar sputtering and substrate conditioning [20,23]. The resonator excitation is generated by a bias  $V_{\text{exc}}$  applied to the quartz sensor [Fig. 1(a)] at a frequency close to  $f_0$ , and the tip oscillation is monitored via the  $I_{\text{osc}}$  current. We used the peak-to-peak oscillation amplitude  $A_{\text{pp}} = 100 \text{ pm}$  for nc-AFM. The oscillation frequency shift  $\Delta f$  is determined from the  $I_{\text{osc}}$  by a phase-locked loop electronics (Nanonis; SPECS, Zürich). The tunneling current  $I_t$  flowing through the grounded tip (with the sample biased at a voltage  $V$ ) is collected by a separate electrode. nc-AFM is obtained after a preliminary STM scan, by passing the tip parallel to the substrate plane and recording  $\Delta f$  for  $V = 0$ . KPFM consists of recording  $\Delta f(V)$  local spectroscopies over a predefined grid (data acquisition of a few hours), with the tip retracted by  $150 \text{ pm}$  from nc-AFM conditions, and using  $A_{\text{pp}} = 200 \text{ pm}$  for noise issues.

### III. nc-AFM AND KPFM IMAGING OF SINGLE IONIZED BURIED DOPANTS

Figure 1(b) shows an empty-state STM image of the surface, with three defects: a subsurface ionized boron dopant [Fig. 1(d)], a surface silicon adatom vacancy [Fig. 1(e)], and an unpassivated surface Si adatom leading to a DB [Fig. 1(f)], highlighted by green, yellow, and white dashed circles, respectively. The defects are also observed in the atomic resolution nc-AFM image in Fig. 1(c) [20] (frequency shift image acquired with  $z$  feedback loop off).

We use KPFM to image the electrostatics of these defects, starting with the buried boron dopant. A control filled-state STM image is shown in Fig. 2(a), together with the  $15 \times 15$  grid used in the spectroscopy experiment. The in-plane drift (here  $<100 \text{ pm/h}$ ) is systematically verified. We checked that the  $\Delta f(V)$  [example in Fig. 2(b)] spectroscopies are hysteresis free. They are analyzed through a quadratic fit,  $A + B \times (V - V_s)^2$ , to experimental data, using the method of least squares.  $A$  is the resonator frequency shift for  $V = V_s$  and accounts for van der Waals, repulsive forces and image charge effects, but also includes a residual offset on the determination of  $f_0$ ;  $B$  accounts for the tip-surface capacitance second derivative; and  $V_s$  is the local surface potential, including electrostatic (i.e., charging) effects. The reconstructed image of  $V_s$  constitutes the KPFM image. Since  $V$  is applied to the sample, a positive (negative) surface charge will be compensated by a negative (positive) surface potential contribution, leading to a dark (bright) feature in the KPFM image. The error on  $V_s$  is defined on each grid point as the sample voltage offset required to increase the residue of the quadratic fit to  $\Delta f(V)$  by a factor of 2, while keeping  $A$  and  $B$  constant.

Grid maps of  $A$  and  $B$  for the buried dopant in Fig. 2(a) are shown in Figs. 2(c) and 2(d). The faint observed evo-

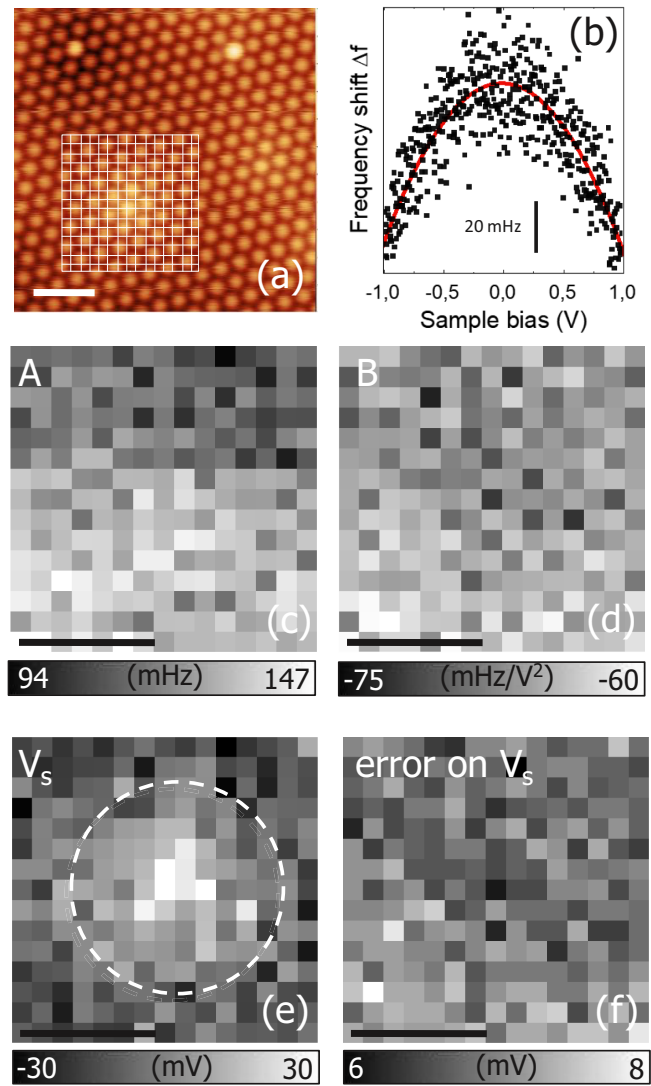


FIG. 2. (a) STM image ( $V = -0.7 \text{ V}$ ,  $I_t = 10 \text{ pA}$ , 2-nm scale bar), together with the  $15 \times 15$  grid used in  $\Delta f(V)$  spectroscopy experiments over an identified buried dopant. (b) Example of a locally acquired  $\Delta f(V)$  spectroscopy curve, together with a quadratic fit,  $A + B \times (V - V_s)^2$ . (c) Reconstructed  $15 \times 15$  grid of the fitted  $A$  parameter (in Hz) over the buried dopant. (d) Grid of the fitted  $B$  parameter (in  $\text{Hz}/\text{V}^2$ ). (e) Grid of fitted  $V_s$  values (KPFM map), showing a highlighted bright feature (negative potential). (f) Reconstructed grid of the fit error on  $V_s$ . Scale bars are 2 nm in (c)–(f).

lution corresponds to a weak vertical drift of the tip. The error on  $V_s$  [Fig. 2(f)] evidences a KPFM accuracy of the order of a few millivolts. The KPFM map [Fig. 2(e)] shows a highlighted bright feature of relative amplitude  $\approx 40 \text{ mV}$  and radius  $\approx 1 \text{ nm}$ . It corresponds to the negative potential expected for the ionized boron dopant ( $-e$  charge). A similar experiment showed no detectable charge for the Si vacancy (Supplemental Material, Fig. S1 [24]). This demonstrates the ability of length-extensional resonators to map single charge features at subnanometer resolution, as expected theoretically [25] and originally achieved using tuning forks [2].

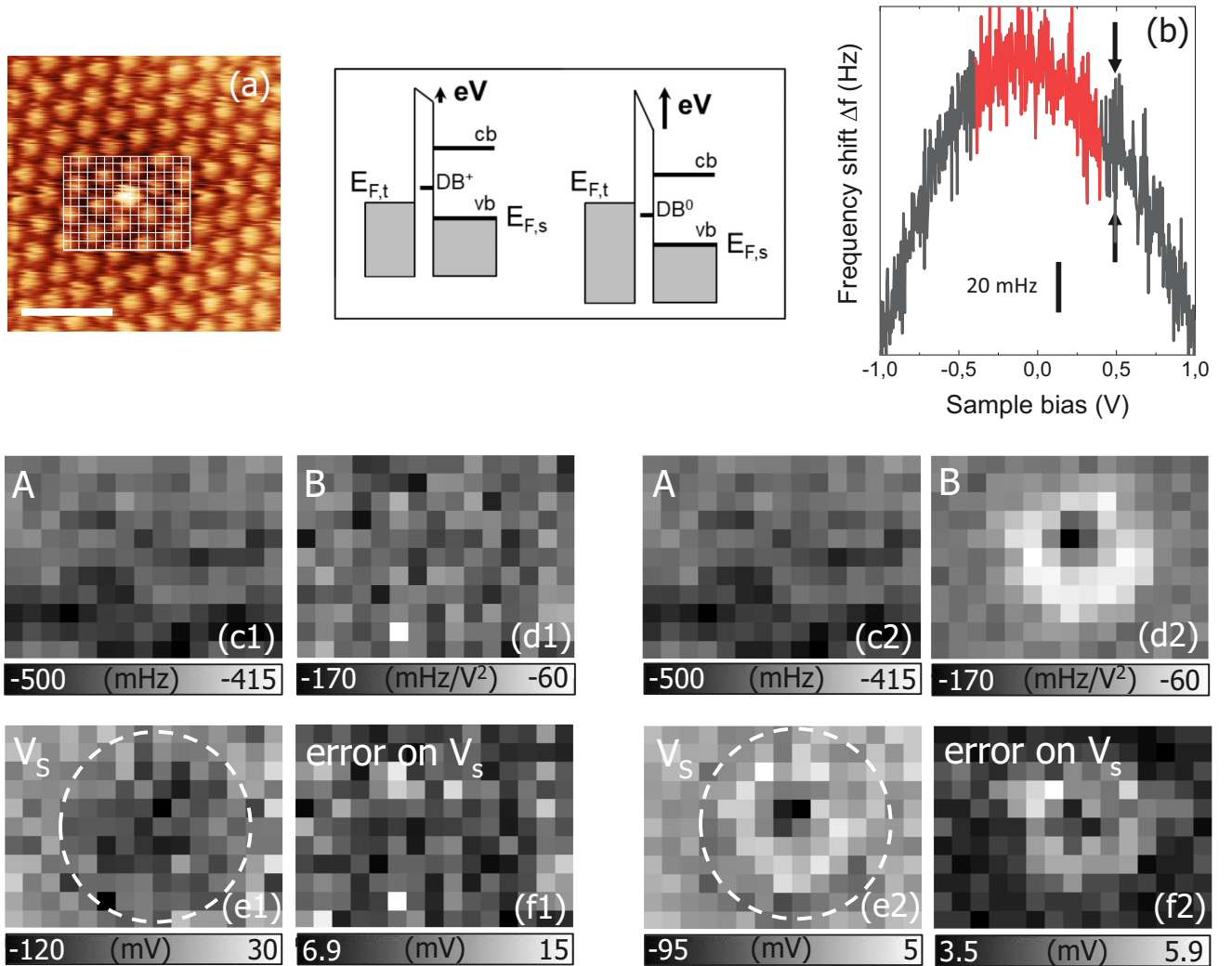


FIG. 3. (a) STM image ( $V = -0.7$  V,  $I_t = 10$  pA, 120-pm color scale, 2-nm scale bar) of a single dangling bond, with the  $11 \times 15$  spectroscopy grid used in KPFM experiments. Inset: Energy diagrams of the tip-substrate junction with a bandgap DB state, in which  $E_{F,t}$  and  $E_{F,s}$  refer to the tip and substrate Fermi levels, and cb and vb to the substrate conduction and valence bands, respectively. Diagrams are shown at a low positive sample bias (left), in which the DB is in the unoccupied  $DB^+$  state, and at a larger positive sample bias (right), for which the DB can be occupied by one electron in the neutral  $DB^0$  state. (b) Example of a  $\Delta f(V)$  spectroscopy showing a nonparabolicity effect (jump marked by arrows). The reduced voltage range in red  $[-0.4$  V;  $+0.4$  V] and the full range  $[-1$  V;  $+1$  V] have been used for the reconstructed grid images of the parameters  $A$ ,  $B$ , and  $V_s$  and the error on  $V_s$  shown in (c1), (d1), (e1), and (f1) and in (c2), (d2), (e2), and (f2), respectively. The  $11 \times 15$  grids in (c1)-(f1) and (c2)-(f2) correspond to image sizes of  $2.05$  nm  $\times$   $2.8$  nm.

#### IV. nc-AFM AND KPFM OF SINGLE SILICON DANGLING BONDS

We now focus on the Si DB, which constitutes the core of our paper. An STM image is given in Fig. 3(a) with the  $11 \times 15$  KPFM grid. Schematic energy diagrams including the bandgap DB state are shown in the inset at small and large positive sample biases. The DB state is electronically unoccupied at a low voltage  $V$  and, thus, carries a charge  $+e$  ( $DB^+$  state). At a higher positive sample voltage, a current can flow through the DB, which can become populated by a single electron (neutral  $DB^0$  state). The actual DB charge actually depends both on the electronic current and on the recombination rate with substrate holes. A DB charging by two electrons ( $DB^-$  state) can also be achieved [10] at a larger

sample bias but is not investigated here. A similar behavior occurs for the DB on the H-Si(100)  $2 \times 1$  surface [11].

We show in Fig. 3(b) a selected example of a  $\Delta f(V)$  spectroscopy showing a nonparabolic feature marked by arrows, at a bias  $V \simeq 0.5$  V. Its origin is discussed hereafter based on the DB charging.  $\Delta f(V)$  data are first analyzed using a small voltage range  $[-0.4$  V;  $0.4$  V] [data points in red in Fig. 3(b)], for which the DB is unoccupied. The grid images for  $A$  and  $B$  [Figs. 3(c1) and 3(d1)] reveal flat contributions, indicating a negligible drift. The image of  $V_s$  [Fig. 3(e1)] shows a dark feature (positive electrostatic potential), while the error on  $V_s$  [Fig. 3(f1)] remains featureless. The observation of a positive electrostatic potential is fully consistent with the  $DB^+$  state expected for the DB at a low sample voltage (Fig. 3, inset). A further comparison of KPFM images for the buried dopant

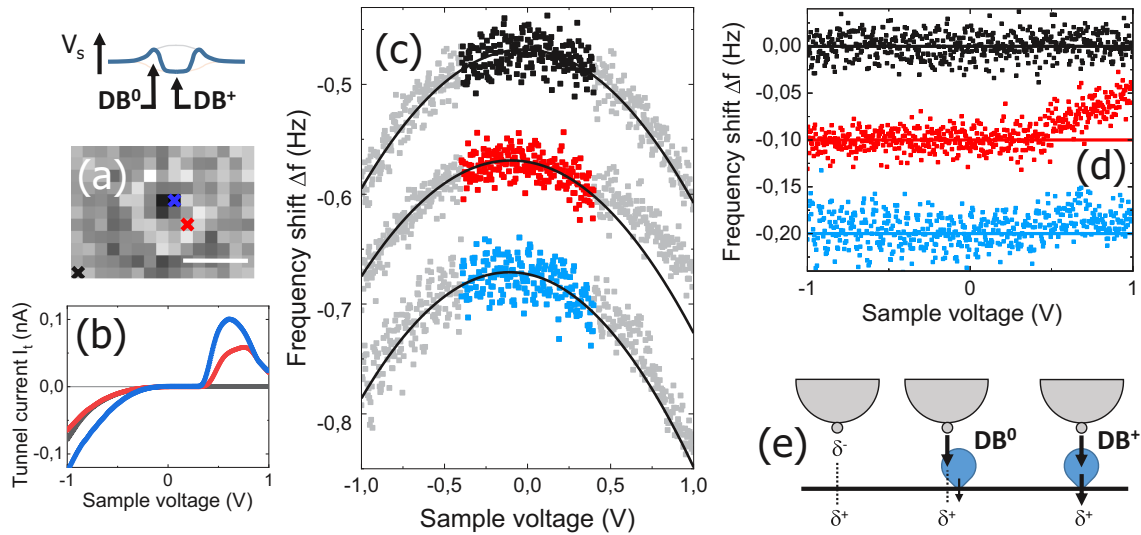


FIG. 4. (a) KPFM spectroscopy grid as in Fig. 3(c2) (1-nm scale bar) with a schematic cross section of the KPFM constrast. (b)  $I_t(V)$  and (c) simultaneously recorded  $\Delta f(V)$  spectroscopies acquired at the marked locations in (a). Colored points in  $\Delta f(V)$  plots highlight the voltage range used for parabolic fits, which are shown as solid lines. (d) Difference between  $\Delta f(V)$  and parabolic fits. (e) Model explaining the ring-shape charging as being due to a modulation of the hole recombination rate (see text).

( $-e$  charge), silicon vacancy (neutral state), and  $DB^+$  ( $+e$  charge) is provided in the Supplemental Material, Fig. S2 [24].

To investigate the nonparabolicities, we reproduced the fitting procedure as in Figs. 3(c1)–3(f1), however, with a larger voltage range  $[-1 \text{ V}; +1 \text{ V}]$ . This analysis is purely phenomenological, since a quadratic model *does not* formally apply at a large positive bias. It, however, enables us to map where the nonparabolicities—and thus the charging effects—spatially occur. Indeed, a nonparabolicity in a  $\Delta f(V)$  leads to fit deviations which impact both the fitted average curvature  $B$  and the surface  $V_s$ . DB fit results using a  $[-1 \text{ V}; +1 \text{ V}]$  voltage range are shown in Figs. 3(c2)–3(f2), as a comparison with images obtained in Figs. 3(c1)–3(f1). Nonparabolicities are observed with a ring shape of radius about 500 pm around the silicon DB, in both the  $V_s$  [Fig. 3(e2)] and the  $B$  [Fig. 3(d2)] images, which are correlated. They also appear in the error on  $V_s$  [Fig. 3(f2)], due to the unsatisfactory use of a quadratic model. The observation of a ring shape means that charging effects are lower at the location of the DB adatom but strikingly enhanced farther away from the adatom. The ring appears as a bright contrast in the KPFM (negative potential), which can be attributed to a local dipolar effect associated with the neutral  $DB^0$  state (see Supplemental Material, Fig. S3 [24]).

We now analyze  $\Delta f(V)$  spectroscopies over the substrate, charging ring, and DB adatom [black, red, and blue points in Fig. 4(a)]. Simultaneously recorded  $I_t(V)$  tunnel spectroscopy data are shown in Fig. 4(b). The  $I_t(V)$  spectroscopy over the substrate is typical of a  $p$ -type semiconductor. The  $Si(111)$ - $(\sqrt{3} \times \sqrt{3})R^{\circ}30$  reconstruction, however, does not exhibit the degenerate character of the bulk Si substrate, as due to surface band bending. This indicates that the free hole density  $p$  at the sample surface is lower than the valence-band effective density of states at  $T = 4 \text{ K}$  ( $p < N_V \simeq 3 \times 10^{16} \text{ cm}^{-3}$ ). The  $I_t(V)$  values acquired on the charging ring and DB adatom reveal the presence of the DB bandgap state, marked by

the prominent peak at  $V \approx 0.7 \text{ V}$ . The marked occurrence of a negative differential conductance is obtained for sub-nanoampere current levels because the tip is oscillated ( $A_{pp} = 200 \text{ pm}$ ). The fact that the DB state is visible in tunneling spectra at both sites is related to the  $\simeq 1$ -nm lateral size of the DB wave function (see Supplemental Material, Fig. S5 [24]). The individual  $\Delta f(V)$  spectroscopies are represented in Fig. 4(c). Colored data points indicate the  $[-0.4 \text{ V}; 0.4 \text{ V}]$  voltage range used to establish the quadratic fit. The difference between the  $\Delta f(V)$  spectroscopies and the extrapolated parabolic fits is represented in Fig. 4(d) in the  $[-1 \text{ V}; +1 \text{ V}]$  voltage range.

## V. DISCUSSION

The previous analysis enables us first to rule out any spurious relationship between  $I_t(V)$  and  $\Delta f(V)$  such as phantom forces [26] or quartz cross-talk effects [27]. In particular, no asymmetry is observed for positive and negative voltages for  $\Delta f(V)$  on the  $p$ -type semiconductor substrate, while the  $I_t(V)$  is highly asymmetric. The absence of deviations for  $\Delta f(V)$  when  $I_t$  is significant is further demonstrated in Fig. 4(d), in which the low-voltage fit to  $\Delta f(V)$  (with  $I_t < 10 \text{ pA}$ ) perfectly applies in the full  $[-1 \text{ V}; 1 \text{ V}]$  range (with  $I_t$  up to 1 nA). Since the average current passed through the DB does not exceed the nanoampere range, this rules out any phantom force effect in the forthcoming analysis.

The analysis done in Fig. 4(d) enables us to further understand DB charging effects. They appear on the charging ring [red curve in Fig. 4(d)] as a linear increase in  $\Delta f(V)$  for  $V > 0.5 \text{ V}$ , with a slope of about 0.065 Hz/V, while only faint deviations with respect to a pure parabolic behavior are observed at the DB site itself [blue curve in Fig. 4(d)]. Averaged data are also available in Supplemental Fig. S4 [24]. The linear behavior is equivalent to a constant surface potential offset  $\delta V_s$ , inducing a linear frequency shift contribution  $2B\delta V_s \times V$ .



This shows, in particular, that the charging does not vary with the sample voltage. Using  $B = 0.13 \text{ V/Hz}^2$  as from the fit in Fig. 4(c), this yields  $\delta V_s = 250 \text{ mV}$  (with a misaccuracy of 10%). The linear fit of  $\Delta f(V)$  for  $V > 0.5 \text{ V}$  also evidences a frequency shift jump at  $V \approx 0.5 \text{ V}$ , of amplitude  $15 \pm 7 \text{ mHz}$ , however close to the experimental noise. We attribute the  $\delta V_s$  value to the transition between the  $\text{DB}^+$  charge state and the  $\text{DB}^0$  charge state. It is, in particular, consistent with a dark-to-bright transition in the KPFM image, since the  $\text{DB}^+$  charge state electrostatic potential is of  $\approx -80 \text{ mV}$  (see Supplemental Material, Fig. S2 [24]).

A phenomenological model explaining the ring-shape transition from the  $\text{DB}^+$  to the  $\text{DB}^0$  charge state is finally proposed in Fig. 4(e). It is based on the shape of the DB wave function, with a lateral extension of about 1 nm on the AFM/STM tip side and a reduced extension on the substrate side. The carrier injection into the DB wave function is governed by the wave-function overlaps between the DB and the tip outermost atom, while the recombination between an electron populating the DB and a substrate hole is more local. The latter process has been treated so far as in bulk semiconductors, with a rate described as  $c \times p$  in which  $c$  is the hole capture coefficient [16]. We propose that tip charging and/or polarization effects can induce the appearance of the charging ring, via the modulation of the hole capture rate  $c \times p$ . Assuming here for discussion a charge picture in which the grounded tip carries a local charge  $\delta^-$  with a corresponding substrate image  $\delta^+$ , for  $V > 0$  (this charge may be replaced by a short-range polarization effect), this local charge follows the outermost tip atom when the tip is scanned over the DB [Fig. 4(e)]. This enhances the recombination rate  $c \times p$  (and thus lowers the average DB electron occupancy) when the tip is above the DB Si adatom. The recombination rate is conversely lower when the tip is positioned at the edge of the wave function. Altogether, this leads to an enhanced

DB charging effect, with a ring shape corresponding to the DB wave-function diameter.  $\delta^+$  can be estimated using the capacitance  $4\pi\epsilon_0 R$  of a sphere with radius  $R = 1.7 \text{ \AA}$  in order to mimic an outermost Si tip adatom, yielding  $\delta^+ \approx 0.05e$  for  $V = 0.5 \text{ V}$ . Even if  $\delta^+$  were “diluted” over a  $1\text{-nm}^3$  volume below the semiconductor surface, one gets  $\delta p \approx$  a few  $10^{16} \text{ cm}^{-3}$ , which falls above the hole density  $p$  at the sample surface. This underlines the efficiency of a tip-induced modulation of  $c \times p$  to explain the DB ring charging. A realistic model, however, clearly lies beyond our work since it will require the exact electronic structure of the  $\text{Si}(111)\text{-}(\sqrt{3} \times \sqrt{3})R^{\circ}30$  surface and the calculation of electrostatic short-range effects, including dipolar [28] and polarization [29] effects, which have been pointed out in the nc-AFM imaging of charged adatoms [2].

## VI. CONCLUSION

In conclusion, we have achieved subnanometer electrostatic mapping of semiconductor defects carrying elementary charges and studied the charging mechanisms of a single Si DB. Remarkably, KPFM spectroscopy revealed nonparabolic features identified as a transition from the inoccupied  $\text{DB}^+$  state to the single-occupied  $\text{DB}^0$  state, with a ring shape localized at the edge of the DB wave function, and attributed to a modulation of the DB hole capture rate at the nanometer scale.

## ACKNOWLEDGMENTS

We acknowledge discussions with M. Berthe and C. Delerue. This work was achieved using the facilities of the EXCELSIOR Nanoscience Characterization Center and of the RENATECH program.

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